

PROCEEDINGS



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**Ralf Widenhorn
Antoine Dupret**
Editors

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Contents

vii *Conference Committee*

SESSION 1 HIGH-SPEED SENSORS

- 9022 02 **A time-resolved image sensor for tubeless streak cameras** [9022-1]
K. Yasutomi, S. M. Han, M.-W. Seo, T. Takasawa, K. Kagawa, S. Kawahito, Shizuoka Univ. (Japan)
- 9022 03 **Pixel structure with 10 nsec fully charge transfer time for the 20m frame per second burst CMOS image sensor (Best Student Paper Award)** [9022-2]
K. Miyauchi, T. Takeda, K. Hanzawa, Y. Tochigi, S. Sakai, R. Kuroda, Tohoku Univ. (Japan); H. Tominaga, R. Hirose, K. Takubo, Y. Kondo, Shimadzu Corp. (Japan); S. Sugawa, Tohoku Univ. (Japan)
- 9022 04 **Novel CMOS time-delay integration using single-photon counting for high-speed industrial and aerospace applications** [9022-3]
M. M. El-Desouki, B. Al-Azem, King Abdulaziz City for Science and Technology (Saudi Arabia)
- 9022 05 **Ultra-high speed video capturing of time dependent dielectric breakdown of metal-oxide-silicon capacitor up to 10M frame per second** [9022-4]
F. Shao, D. Kimoto, K. Furukawa, H. Sugo, T. Takeda, K. Miyauchi, Y. Tochigi, R. Kuroda, S. Sugawa, Tohoku Univ. (Japan)

SESSION 2 SMART SENSORS

- 9022 06 **Low data rate architecture for smart image sensor** [9022-5]
A. Darwish, G. Sicard, L. Fesquet, TIMA Lab., CNRS, Univ. Grenoble Alpes (France)
- 9022 07 **Frameless, time domain continuous image capture** [9022-6]
H. G. Dietz, Univ. of Kentucky (United States)
- 9022 09 **Smart imaging for power-efficient extraction of Viola-Jones local descriptors (Best Paper Award)** [9022-8]
J. Fernández-Berni, R. Carmona-Galán, R. del Río, J. A. Leñero-Bardallo, IMSE-CNM (Spain) and Univ. de Sevilla (Spain); M. Suárez-Cambre, Univ. de Santiago de Compostela (Spain); Á. Rodríguez-Vázquez, IMSE-CNM (Spain) and Univ. de Sevilla (Spain)

SESSION 3 HIGH-PERFORMANCE SENSORS

- 9022 0A **Time-to-digital converter based on analog time expansion for 3D time of flight cameras** [9022-9]
M. Tanveer, Luleå Univ. of Technology (Sweden); I. Nissinen, J. Nissinen, J. Kostamovaara, Univ. of Oulu (Finland); J. Borg, J. Johanson, Luleå Univ. of Technology (Sweden)
- 9022 0B **Experiment on digital CDS with 33-M pixel 120-fps super hi-vision image sensor** [9022-10]
J. Yonai, T. Yasue, K. Kitamura, T. Hayashida, NHK Science and Technology Research Labs. (Japan); T. Watabe, NHK Engineering Services, Inc. (Japan); H. Shimamoto, NHK Science and Technology Research Labs. (Japan); S. Kawahito, Shizuoka Univ. (Japan)
- 9022 0C **Pixel structure for asymmetry removal in ToF 3D camera** [9022-11]
B. Kang, J. Shin, J. Choi, J. D. K. Kim, Samsung Advanced Institute of Technology (Korea, Republic of)
- 9022 0D **A stimulated Raman scattering imager using high-speed lateral electric field modulator and lock-in pixels amplifiers** [9022-12]
K. Mars, B. Guseul, H. S. Man, T. Takasawa, K. Yasutomi, K. Kagawa, Shizuoka Univ. (Japan); M. Hashimoto, Osaka Univ. (Japan); S. Kawahito, Shizuoka Univ. (Japan)

SESSION 4 NOISE AND CHARACTERIZATION

- 9022 0E **Estimating an image sensor's temperature for darksignal-correction** [9022-13]
J. Achatzi, G. Fischer, Fachhochschule Köln (Germany); V. Zimmer, Leica Camera AG (Germany); D. Paulus, Univ. Koblenz-Landau (Germany)
- 9022 0F **A statistical evaluation of effective time constants of random telegraph noise with various operation timings of in-pixel source follower transistors** [9022-14]
A. Yonezawa, R. Kuroda, A. Teramoto, T. Obara, S. Sugawa, Tohoku Univ. (Japan)
- 9022 0G **Correcting high density hot pixel defects in digital imagers** [9022-15]
G. H. Chapman, R. Thomas, Simon Fraser Univ. (Canada); Z. Koren, I. Koren, Univ. of Massachusetts Amherst (United States)
- 9022 0H **Comparison of two optimized readout chains for low light CIS** [9022-16]
A. Boukhayma, CEA-LETI (France) and Ecole Polytechnique Fédérale de Lausanne (Switzerland); A. Peizerat, A. Dupret, CEA-LETI (France); C. Enz, Ecole Polytechnique Fédérale de Lausanne (Switzerland)
- 9022 0I **Review of ADCs for imaging** [9022-17]
J. A. Leñero-Bardallo, J. Fernández-Berni, Á. Rodríguez-Vázquez, IMSE-CNM (Spain) and Univ. de Sevilla (Spain)

SESSION 5 TECHNOLOGICAL IMPROVEMENTS

- 9022 0J **Color image sensor using stacked organic photoconductive films with transparent readout circuits separated by thin interlayer insulator** [9022-18]
T. Sakai, H. Seo, S. Aihara, H. Ohtake, M. Kubota, NHK Science and Technology Research Labs. (Japan); M. Furuta, Kochi Univ. of Technology (Japan)
- 9022 0K **Real-time compact multispectral imaging solutions using dichroic filter arrays** [9022-19]
E. V. Chandler, D. E. Fish, Pixelteq, Inc. (United States)
- 9022 0L **A 1024×1 linear photodiode array sensor with fast readout speed flexible pixel-level integration time and high stability to UV light exposure** [9022-20]
T. Akutsu, S. Kawada, Y. Koda, T. Nakazawa, R. Kuroda, S. Sugawa, Tohoku Univ. (Japan)
- 9022 0M **A high fill-factor low dark leakage CMOS image sensor with shared-pixel design** [9022-21]
M.-W. Seo, K. Yasutomi, K. Kagawa, S. Kawahito, Shizuoka Univ. (Japan)
- 9022 0N **Co-integration of a smart CMOS image sensor and a spatial light modulator for real-time optical phase modulation** [9022-22]
T. Laforest, A. Verdant, A. Dupret, CEA-LETI-MINATEC (France); S. Gigan, F. Ramaz, ESPCI ParisTech, Institut Langevin, CNRS (France); G. Tessier, Neurophysiology and New Microscopies Lab., CNRS, Univ. Paris Descartes (France)

SESSION 6 APPLICATIONS

- 9022 0P **A CMOS time-of-flight range image sensor using draining only modulation structure** [9022-24]
S. Han, K. Yasutomi, K. Kagawa, S. Kawahito, Shizuoka Univ. (Japan)
- 9022 0Q **A high speed 2D time-to-impact algorithm targeted for smart image sensors** [9022-25]
A. Åström, Combitech AB (Sweden); R. Forchheimer, Linköping Univ. (Sweden)
- 9022 0R **Real-time 3D millimeter wave imaging based FMCW using GGD focal plane array as detectors** [9022-26]
A. Levanon, D. Rozban, N. S. Kopeika, Y. Yitzhaky, Ben-Gurion Univ. of the Negev (Israel); A. Abramovich, Ariel Univ. (Israel)

INTERACTIVE PAPER SESSION

- 9022 0T **Iterative compressive sampling for hyperspectral images via source separation** [9022-28]
S. Kamdem Kuiteing, M. Barni, Univ. degli Studi di Siena (Italy)
- 9022 0V **Hyperspectral imaging applied to end-of-life concrete recycling** [9022-30]
S. Serranti, G. Bonifazi, Univ. degli Studi di Roma La Sapienza (Italy)

- 9022 0W **An indirect time-of-flight measurement technique for sub-mm range resolution using impulse photocurrent response** [9022-31]
T. Usui, K. Yasutomi, H. S. Man, T. Takasawa, K. Kagawa, S. Kawahito, Shizuoka Univ. (Japan)
- 9022 0X **Theoretical study of an efficient bracketing camera system architecture** [9022-32]
A. Besrour, Univ. of Carthage (Tunisia); H. Snoussi, Univ. de Technologie Troyes (France);
M. Siala, F. Abdelkefi, Univ. of Carthage (Tunisia)

Author Index

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2 Smart Sensors

Morley M. Blouke, Portland State University (United States)

Alice L. Reinheimer, e2v (United States)

3 High-Performance Sensors

Kevin J. Matherson, Microsoft Corporation (United States)

- 4 Noise and Characterization
Boyd A. Fowler, Google (United States)
Antoine Dupret, Commissariat à l'Énergie Atomique (France)
- 5 Technological Improvements
James A. DiBella Sr., Truesense Imaging, Inc. (United States)
Nobukazu Teranishi, University of Hogo (Japan) and Shizuoka University (Japan)
- 6 Applications
Arnaud Darmont, Aphesa SPRL (Belgium)